## PRESENTATION GUIDELINES

# Government Agencies Technology Exchange in Manufacturing (GATE-M)

### INTERAGENCY PROGRAM REVIEW

June 24-25, 2003

The GATE-M Interagency Program Review will consist of agency-level overview presentations, along with specific program presentations from each of the six GATE-M agencies. The program presentations will focus on the two technical areas that have been identified for joint address by GATE-M: *Intelligence in Manufacturing, and Nano-/Micro-Scale Systems and Technologies*. It is expected that the primary participants in the Review will be program manager-level personnel from the GATE-M agencies who are involved in the daily operation and technical progress of agency programs in these two areas.

The purpose of the Review is to provide a forum for the federal agencies that have manufacturing in their missions to exchange program-level information about agency activities in the two focus areas. It is anticipated that the review will result in the identification of opportunities for collaboration, coordination, and leverage among the agencies in these areas, as well as the identification of agency priorities in the areas, along with gaps in addressing them.

In a broad sense, the Review also aims to cultivate a greater understanding within the agencies about the manufacturing R&D programs occurring across the federal government. The Review is seen as a vital step in fostering opportunities for interagency collaboration in specific areas as a means to facilitate leveraged, coordinated, and even jointly planned and conducted efforts.

The Review agenda is available on the GATE-M website, located at www.mel.nist.gov/gatem

#### **Guidance for Agency Overview Presentations**

- Each agency will provide a 20-minute agency overview presentation to start the Review on June 24.
- The GATE-M Panel principals will provide these presentations.
- Agency overview presentations should focus on the following:
  - 1. description of the agency s mission
  - 2. description of how manufacturing fits into the agency s mission and why manufacturing is important to the agency

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- <u>3.</u> high-level summary of the agency s manufacturing programs, activities, and interests, including discussion of agency program selection strategies
- 4. summary of the agency s interest in and expectations of GATE-M
- 5. agency contact information

#### **Guidance for Agency Program Presentations**

- Each agency will provide program-level presentations describing the agency work and interests relating to each of the two technical areas: Intelligence in Manufacturing and Nano- / Micro-Scale Systems and Technologies. Each agency will have one hour and fifteen minutes for its presentations in each area.
- These program presentations should nominally be provided by the program managerlevel personnel from the agencies who are involved in the daily operation, direction, and technical progress of the agency programs in the two areas.
- Program presentations should focus on the following:
  - 1. goals and objectives
  - 2. technical approach overview
  - 3. summary of status and accomplishments
  - 4. critical needs and future directions
  - 5. current collaborators and future opportunities
  - 6. level-of-effort indication of program funding
  - 7. contact information

All presentations should be submitted in electronic format to David Stieren on behalf of the GATE-M Panel one week before the Review, or by COB on Monday, June 16, 2003. E-mail is preferred for these submissions; however, if presentations are too large to e-mail, they should be placed on CD, Zip disk, or floppy disk, and mailed.

E-mail presentations to: <u>david.stieren@nist.gov</u>

or

Mail disks to: David Stieren

NIST Manufacturing Engineering Laboratory

100 Bureau Drive, Stop 8200 Gaithersburg, MD 20899-8200

Presentations will be pre-loaded and projected electronically during the Review from a PC, so all presentation software that is used should be compatible with a PC operating Windows (Powerpoint or .pdf files are recommended). Also, hardcopies of presentations will be provided to Review attendees.

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